Day 1 2025/6/18

			session	Туре	Speaker	Affiliations	Title	
13:00		13:10		Opening	Kousuke Moritani	University of Hyogo		
13.00	1 -	13.10	'	remarks	Satoka Aoyagi	Seikei University		
13:10		13:40		Invited Noriaki Toyoda	Nerieki Teyede	University of Hyogo	Effects of Gas Cluster Ion Impacts and Its	
15:10	-	13:40			Noriaki Toyoda		Application to Surface Characterization	
		14:10	Scattering:Insights into Material Hardness	Invited Kousuke M			Dissociative Scattering of Argon Clusters:	
13:40	-				Kousuke Moritani	University of Hyogo	Fundamental Insights into	
							Surface Mechanical Properties	
		14:40		Invited Hiroshi Tani			Application of Ultra-Thin Film Elastic	
14:10	-				Hiroshi Tani	Kansai University	Modulus Measurement Using Ar Gas	
							Cluster Ion Beam to Tribology	
14:40	-	14:55		Coffee Break				
14:55		15:25		Invited	nvited Arnaud D. Delcorte	Université catholique de Louvain	Gas cluster ion beam scattering (GCISS) for	
14.55	-		Session 1-(2)	Amada D. Delcorte	Oniversite catholique de Louvain	polymer surface physics studies		
15:25		15:55	Cluster Collision and Scattering:Insights into	Invited Lu-Tao Weng	Lu Too Mong	The Hong Kong University of Science	Impacts of Cluster Ion Sources on Polymer	
15.25	1 -				and Technology (Guangzhou)	Thin Film Analysis		
15:55		Mater 16:25	Material Hardness	Invited Naoko Sano	lanantika	Potential novel applications for GCIBs in		
15:55	-			invited	ivacko Sano	lonoptika	SIMS	
16:25	-	17:00	Poster session	Short Presentation				
17:00	-	18:30	Fusier Session	Poster				
18:45	-	20:45		Social gathering				

Day 2	202	5/6/19					
			session	Туре	Speaker	Affiliations	title
9:30	- 1	9:40		Opening remarks	Toshio Seki	Kyoto University	
9:40	- 1	10:20	Session 2-(1) Jiro Matsuo Memorial Session	Memorial Lecture	Jiro Matsuo	Kyoto University	Chemical structure of sputtered molecules with large cluster ions and its impact on SIMS technique
10:20	-	10:45		JM Invited	Satoshi Ninomiya	University of Yamanashi	Droplet Ion Beams Produced by Vacuum Electrospray
10:45	-	11:00	Coffee Break				
11:00	-	11:25	Session 2-(2) Jiro Matsuo Memorial Session	JM Invited	Roger P. Webb	University of Surrey	Combining MeV Ion Beam Analysis with SIMS.
11:25	- 1	11:50		JM Invited	Michael Dürr	Justus Liebig University Giessen	lon-induced fragmentation of soft matter studied with cluster-induced desorption/ionization mass spectrometry
11:50	1	12:15		JM Invited	Hubert Gnaser	University of Vienna	Enthusiasm for argon cluster-ion sputtering (··· in Jiro Matsuo's lab)
12:15	-	13:45	Lunch				
13:45	1	14:10	Session 2-(3) Jiro Matsuo Memorial Session	JM Invited	Zbigniew Postawa	Jagiellonian University	Molecular Dynamics Simulations of Cluster Projectile Bombardment: From Solids to Liquids and 2D Systems
14:10	-	14:35		JM Invited	Nick Lockyer	University of Manchester	Water-assisted SIMS using Gas Cluster Ion Beams
14:35		15:00		JM Invited	John S. Fletcher	University of Gothenburg	GCIB-SIMS studies of lymphoma
15:00	-	15:20	Conference Photo				
15:20	-	15:35				Coffee Break	
15:35	- 1	15:55		Maker	Markus Terhorst	IONTOF	Latest news and historical reviews from IONTOF
15:55	1	16:15	Session 3 Maker Session	Maker	Gabriele Di Stadio	ULVAC PHI	Surface Characterization of Cutting-edge Energy Devices Using PHI nanoTOF3+
16:15	-	16:35		Maker	Naoko Sano	lonoptika (TOYAMA)	Unlocking your analysis at Cryo temperatures
16:35	-	16:55		Maker	Adrien Vuillaume	CAMECA	Measuring isotopic compositions of fluid inclusions under cryogenic conditions with the new CAMECA NanoSIMS-HR
16:55	-	17:20	Session 2-(4) Jiro Matsuo Memorial Session	JM Invited	Ian Gilmore	National Physical Laboratory	Cryo-OrbiSIMS – high resolution mass spectrometry imaging in the native biological state
18:00	-	20:00				Banquet	

Day 3 2025/6/20

Day 3	202	5/6/20					
			session	Туре	Speaker	Affiliations	title
9:30	-	9:50		Oral	Hua Tian	University of Pittsburgh	Delineating Spatial Cellular Complexities Using Multi-omics Approach by GCIB-SIMS
9:50	-	10:20	Session 4 Biotechnology	Invited	Guido Schmitz	University of Stuttgart	Breaking the materials barrier: Atom probe tomography for the chemical analysis of soft matter and complex interfaces
10:20	1	10:50		Invited	Jin Gyeong Son	Korea Research Institute of Standards a	Mass Spectrometry Imaging Approaches for Neurodegenerative Disease Models: From Sample Preparation to Chemical Landscape Exploration
10:50	-	11:05				Coffee Break	
11:05	- 1	11:35	Session 5a Applications	Invited	Motoo Ito	JAMSTEC	From Macro to Sub-micron: A Cross- Platform Pipeline for Extraterrestrial Sample Analysis
11:35		12:05		Invited	Lei Zhang	Chinese Academy of Sciences	TOF-SIMS: A Key Player at the Frontier of Materials Research
12:05	-	13:15				Lunch	
13:15	-	13:25		ı	Cerer	mony for Karen award winner	
13:25	1	13:55		Invited	Takashi Iwanami	Western Digital Technologies GK	TOF-SIMS determination of molecular weight of lubricant oil after head disk interaction in Hard Disk Drive
13:55	-	14:25	Session 5p Applications	Invited	Haiyang Li	Chinese Academy of Sciences	Correlated Microscope/ High Resolution TOF-SIMS Imaging Mass Spectrometry with Continuous Ion Beam
14:25	-	14:45		Oral	Michael J. Eller	California State University Northridge	Challenges in Extreme Ultra Violet Materials and Opportunities for Novel SIMS Methods
14:45	-	15:00	Coffee Break				
15:00	-	15:20		Oral	Markus Langner	California State University Northridge	Analysis of byproducts in CAR photoresists using NP-SIMS
15:20		15:40		Oral	Tetsuya Masuda	Seikei University	Development of an organic molecule prediction system from ToF-SIMS spectra using random forest
15:40	1	16:00	Session 6-(1) (Young scientist Session)	Oral	Anna Kotowska	University of Nottingham	Molecular orientation and stratification revealed in RNA-lipid nanoparticles using Cryogenic Orbitrap Secondary Ion Mass Spectrometry (Cryo-OrbiSIMS)
16:00	- 1	16:20		Oral	Joseph Roberts	University of Nottingham	A novel insight into the metabolic impact of lipid nanoparticle vaccine delivery using OrbiSIMS
16:20	-	16:35				Coffee Break	
16:35	-	16:55		Oral	Yuri Mizutani	Kyoto University	Molecular damage to mPEG molecules by Ar-GCIB sputtering
16:55	-	17:15	Session 6-(2) (Young scientist Session)	Oral	Masaya Takeuchi	University of Hyogo	High-Sensitivity Energy Dispersive X-Ray Spectroscopy Using a Liquid Cell with an Electron-Transmittance Window Ultra- Thinned by Gas Cluster Ion Beam Processing
17:15	-	17:35		Oral	Samuel Bertolini	Université Catholique de Louvain	Soft landing of lysozyme and neurotensin in polyethylene oxide
17:35	-	17:40		Closing	Toshio Seki	Kyoto University	

Poster

	Speaker	Affiliations	title
1	Pei-Cheng Jiang	Minghsin University of Science and	The stability investigation of interfaces between ferromagnetic films and flexible
		Technology	substrate combing the analysis of SIMS and magnetic proximity effect
2	Cheng-Hsun-Tony Chang	Minghsin University of Science and Technology	The relevant research between chemical evolution and tuning magnetic properties of 2D ferromagnet VSe2 in diluted oxygen environment
3	Satoka Aoyagi	Seikei University	Hopfield Network and SIMS Data
4	Daito Jin	Seikei University	Investigation of complex SIMS data of ancient hearth stones in late Pleistocene using unsupervised machine learning
5	Junichiro Takikawa	Kogakuin University	TOF-SIMS Analysis of Single Cell using the Rapid Freezing Method
6	Masaki Hachiya	FUJIFILM Corporation	Sample collection and low-energy analysis by using Ar-GCIB
7	Gan Quan	Kyoto University	Development of in-situ MeV-SIMS technology for lithium-ion batteries
8	Takashi Miyamoto	Toray Research Center, Inc.	Study on the Relationship Between Primary Ion Acceleration Voltage and Local Temperature Using SIMS-OES Method
9	Reo Nukui	Kogakuin University	Analysis of Alteration of Yellow Sands through Chemical Reaction in Air Using FIB-TOF-SIMS
10	Masayuki Hatada	Toray Research Center, Inc. (Retired)	Observation of topography development on Si surface caused by oblique incident O2+ ion beam over a range of ion parameters
11	Ryosuke Shokatsu	University of Hyogo	Dissociation behavior of water gas cluster ions on polycrystalline graphite
12	Azumi Nomura	University of Hyogo	Analysis of TOF-SIMS data of polymer mixture samples using correlation analysis
13	Ayana Sanada	University of Hyogo	Influence of surface roughness on dissociative scattering of Ar cluster ions
14	Taichi Suda	Toray Research Center, Inc.	The sensitivity of molecular secondary ion of metal element related with oxygen at sample surface in NanoSIMS50L
15	Kousuke Moritani	University of Hyogo	E/n dependent desorption and ionization of benzylpyridinium by water cluster ion